Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,565	NIE ET AL.
Examiner	Art Unit
Anthony Weier	1761

			<u> </u>		
	SEARCHED				
Class	Subclass	Date	Examiner		
updated	previous search	7/16/2007	AW		
		·			
			,,		
:					

TNI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
		·
·		
•		
	1	l